



# SEMIPROBE®

Test • Inspect • Innovate

## SUCCESSFUL APPLICATION: HIGH FREQUENCY - 1221



### Specific Requirements:

The customer was looking for a general-purpose 200 mm manual high frequency (HF) wafer probe system that allowed for the measurement of whole wafers up to 200 mm and individual parts mounted on tape over a variety of frequency ranges. They wanted to use individual manual manipulators with standard west/east HF probe arms that could handle GS, SG, GSG, differential, and multi-contact wedges operating from DC to 40 GHz. In addition, they needed the ability to add manual manipulators for DC bias and a probe card holder for probe cards.

### SemiProbe Solution:

- PS4L M-8 manual 200 mm probe system:
  - Rapid Align manual wafer stage with coarse and fine stage travel
  - 200 mm HF chuck with vacuum holes, two auxiliary chucks for calibration substrates
  - Large platen with stainless steel skin, removable front wedge and linear lift
- Microscope:
  - Microscope post with 100 mm of linear X, Y microscope movement
  - Stereo zoom microscope with a long working distance and field of view
  - CCTV system
- Manipulators with magnetic bases:
  - Two MA-9100 manual manipulators with west/east HF arms
  - Two MA-9000 manual manipulators with adjustable probe arm faceplate, coaxial arms
  - Variety of tungsten probe tips for DC bias, HF probe tips, GGB Industries calibration substrates, Junkosha high-frequency cables
- 4.5" probe card holder